

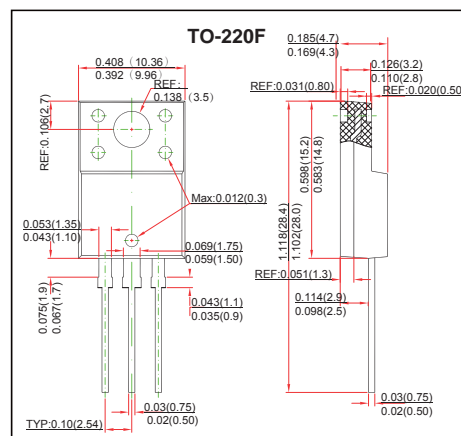
TO-220F Plastic-Encapsulate MOSFETS

Features

- $R_{DS(ON)} = 3.8\Omega @ V_{GS} = 10V$.
- Low gate charge (typical 9.0 nC).
- Low C_{rss} (typical 5.0 pF).
- Fast switching capability.
- Avalanche energy specified Improved dv/dt capability.
- N-Channel MOSFET

MECHANICAL DATA

- Case style: TO-220F molded plastic
- Mounting position: any



MAXIMUM RATINGS AND CHARACTERISTICS

@ 25°C Ambient Temperature (unless otherwise noted)

| Parameter | Symbol | Rating | Unit |
|---|-----------------|------------------|------|
| Drain-Source Voltage | V_{DS} | 600 | V |
| Gate-Source Voltage | V_{GS} | ± 30 | V |
| Drain Current - Continuous ($T_c = 25^\circ\text{C}$) | I_D | 2.0 | A |
| Continuous ($T_c = 100^\circ\text{C}$) | | 1.26 | |
| Drain Current - Pulsed * 1 | I_{DP} | 8.0 | A |
| Single Pulsed Avalanche Energy * 2 | EAS | 140 | mJ |
| Avalanche Current * 1 | I_{AR} | 2.0 | A |
| Repetitive Avalanche Energy * 1 | EAR | 4.5 | mJ |
| Peak Diode Recovery dv/dt * 3 | dv/dt | 4.5 | V/ns |
| Power Dissipation ($T_c = 25^\circ\text{C}$) | P_D | 44 | W |
| Derate above 25 °C | | 0.36 | |
| Operating and Storage Temperature Range | T_J, T_{stg} | - 5 5 to + 1 5 0 | °C |
| Maximum lead temperature for soldering purposes, 1/8" from case for 3 seconds | T_L | 300 | °C |
| Thermal Resistance, Junction-to-Case | $R_{\theta JC}$ | 4 | °C/W |
| Thermal Resistance, Junction-to-Ambient | $R_{\theta JA}$ | 54 | °C/W |

* 1. Repetitive Rating : Pulse width limited by maximum junction temperature.

* 2. L = 64mH, $I_{AS} = 2.0A$, $V_{DD} = 50V$, $R_{\theta} = 25^\circ\text{C}$, Starting $T_J = 25^\circ\text{C}$

* 3. $I_{SD} \leq 2.4A$, $di/dt \leq 200A/\mu s$, $V_{GS} \leq V_{DD}$, BV_{DS} , Starting $T_J = 25^\circ\text{C}$

MOSFET ELECTRICAL CHARACTERISTICS $T_A = 25^\circ\text{C}$ unless otherwise specified

| Parameter | Symbol | Test conditons | Min | Typ | Max | Unit |
|---|--------------|--|-----|------|------|----------|
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0V, I_D = 250\mu A$ | 600 | | | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 600V, V_{GS} = 0V$ $V_{DS} = 480V, T_c = 125^\circ\text{C}$ | | | 10 | μA |
| Gate-Body Leakage Current, Forward | I_{GSSF} | $V_{GS} = 30V, V_{DS} = 0$ | | | 100 | nA |
| Gate-Body Leakage Current, Reverse | I_{GSSR} | $V_{GS} = -30V, V_{DS} = 0V$ | | | -100 | nA |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\mu A$ | 2.0 | | 4.0 | V |
| Static Drain-Source On-Resistance | $R_{DS(on)}$ | $V_{GS} = 10V, I_D = 1A$ | | 3.8 | 5.0 | Ω |
| Forward Transconductance | g_{FS} | $V_{DS} = 50V, I_D = 1A$ * 1 | | 2.25 | | S |
| Input Capacitance | C_{iss} | $V_{DS} = 25V, V_{GS} = 0V, f = 1.0MHz$ | | 270 | 350 | pF |
| Output Capacitance | C_{oss} | | 40 | 50 | pF | |
| Reverse Transfer Capacitance | C_{rss} | | 5 | 7 | pF | |
| Turn-On Delay Time | $t_{d(on)}$ | | 10 | 30 | ns | |
| Turn-On Rise Time | t_r | $V_{DD} = 300V, I_D = 2.4A, R_{\theta} = 25^\circ\text{C}$ * 1,2 | | 25 | 60 | ns |
| Turn-Off Delay Time | $t_{d(off)}$ | | 20 | 50 | ns | |
| Turn-Off Fall Time | t_f | | 25 | 60 | ns | |
| Total Gate Charge | Q_g | $V_{DS} = 480V, I_D = 2.4A, V_{GS} = 10V$ * 1,2 | | 9 | 1 | nC |
| Gate-Source Charge | Q_{gs} | | 1.6 | 1 | nC | |
| Gate-Drain Charge | Q_{gd} | | 4.3 | | nC | |
| Maximum Continuous Drain-Source Diode Forward Current | I_S | | | | 2 | A |
| Maximum Pulsed Drain-Source Diode Forward Current | I_{SM} | | | | 8 | A |
| Drain-Source Diode Forward Voltage | V_{SD} | $V_{GS} = 0V, I_S = 2.0A$ | | | 1.4 | V |
| Reverse Recovery Time | t_{rr} | $V_{GS} = 0V, I_S = 2.4A$ | | 180 | | ns |
| Reverse Recovery Charge | Q_{rr} | $dI_F / dt = 100A/\mu s$ * 1 | | 0.72 | | μC |

* 1. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

* 2. Essentially independent of operating temperature.